

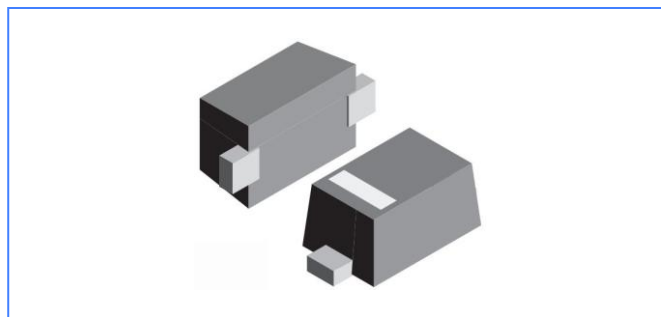
ESD8V0D5

Description

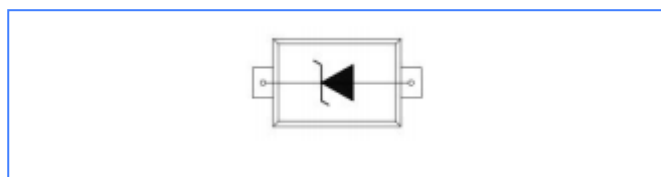
ESD8V0D5 is designed to protect voltage sensitive components from ESD and transient voltage events. Excellent clamping capability, low leakage, and fast response time, make these parts ideal for ESD protection on designs where board space is at a premium.

Features

- 200 Watts Peak Pulse Power per Line ($t_p=8/20\mu s$)
- Operating voltage: 8V
- Low leakage current
- Package: SOD-523
- Low clamping voltage
- Complies with following standards:
 - IEC 61000-4-2 (ESD) immunity test
 - Air discharge: $\pm 15kV$
 - Contact discharge: $\pm 8kV$



Functional Diagram



Applications

- Cellular Handsets and Accessories
- Portable Electronics
- Industrial Controls
- Set-Top Box
- Instrumentation
- Servers, Notebook, and Desktop PC
- Display Ports

Absolute Maximum Ratings($T_{amb}=25\text{ }^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Peak Pulse Power (8/20 μs)	P_{PP}	200	Watts
ESD per IEC 61000-4-2 (Air)	V_{ESD}	± 15	KV
ESD per IEC 61000-4-2 (Contact)		± 8	KV
Lead Soldering Temperature	TL	260 (10 sec)	$^{\circ}\text{C}$
Operating Temperature Range	T_J	-55 to +125	$^{\circ}\text{C}$
Storage Temperature Range	T_{STJ}	-55 to +150	$^{\circ}\text{C}$

Electrical Characteristics (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Units
Reverse Stand-off Voltage	VRWM				8	V
Reverse Breakdown Voltage	VBR	It = 1mA	8.5			V
Reverse Leakage Current	IR	VR = VRWM			5	μA
Clamping Voltage	VC	I _{PP} =1A, t _P = 8/20μs			13	V
Clamping Voltage	VC	I _{PP} =5A, t _P = 8/20μs			20	V
Junction Capacitance	CJ	VR=0V, f = 1MHz			70	pF

Characteristics Curves

Figure 1- Power Derating Curve

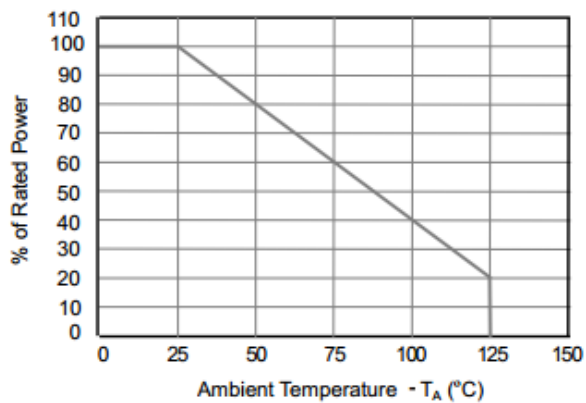
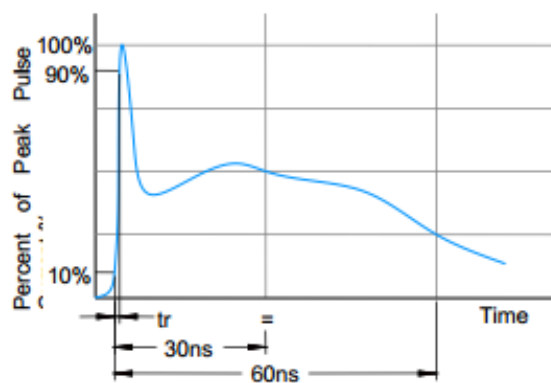
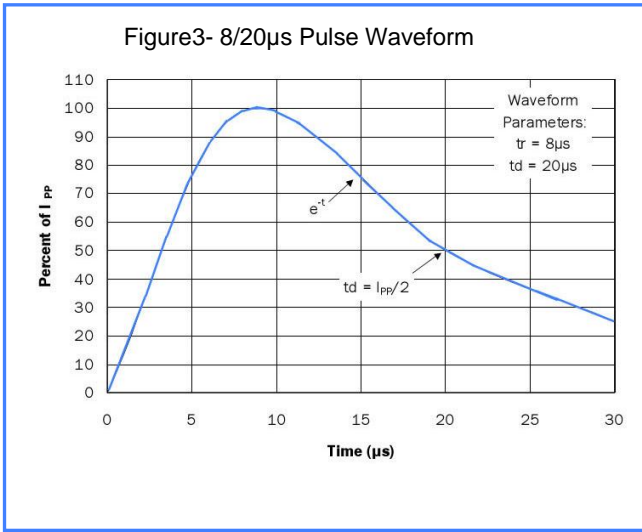
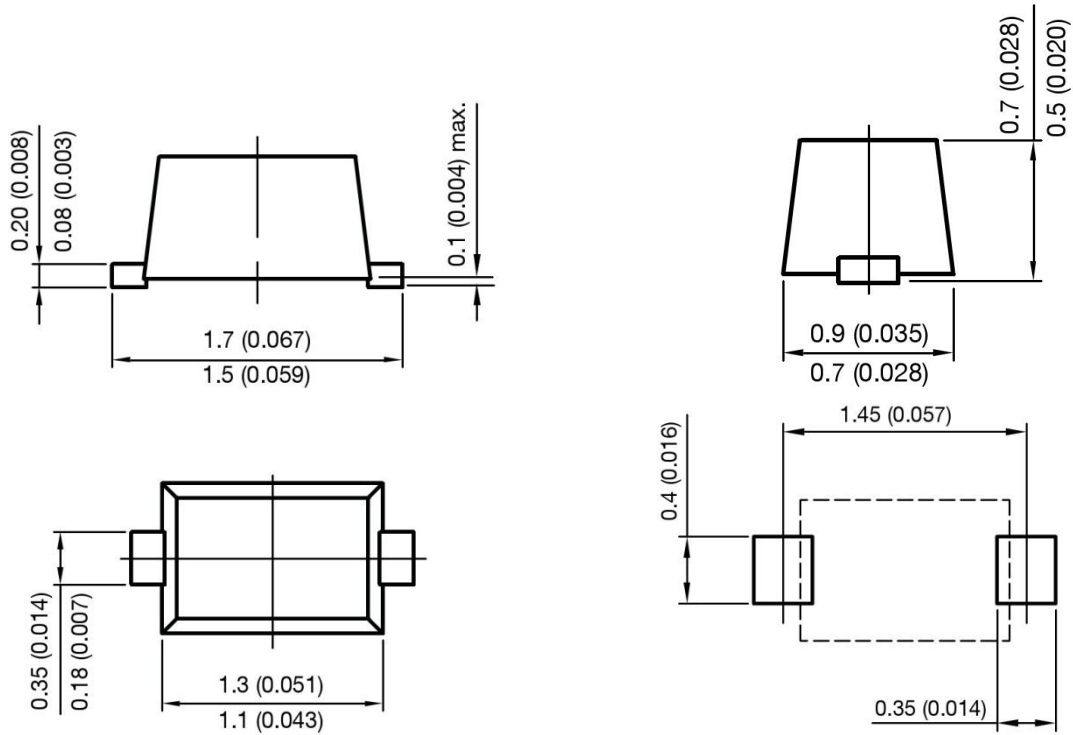


Figure 2- ESD Pulse Waveform (according to IEC 61000-4-2)





PACKAGE OUTLINE DIMENSIONS in millimeters (inches) :SOD523



Mounting Pad Layout

Disclaimer

Specifications are subject to change without notice.
 The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.
 Users should verify actual device performance in their specific applications.